

# C2M0045170P

Silicon Carbide Power MOSFET  
C2M™ MOSFET Technology  
N-Channel Enhancement Mode

## Features

- 2nd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- 8mm of creepage distance between drain and source
- High blocking voltage with low On-Resistance
- High speed switching with low capacitances
- Resistant to latch-up
- Halogen Free, RoHS Compliant

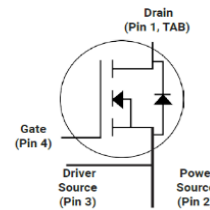
## Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

## Applications

- Solar inverters
- Switch Mode Power Supplies
- High voltage DC/DC converters
- Motor drive
- Pulsed power applications

## Package



Part Number	Package	Marking
C2M0045170P	TO-247-4L	C2M0045170P

## Maximum Ratings ( $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DSmax}$	Drain - Source Voltage	1700	V	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	
$V_{GSmax}$	Gate - Source Voltage	-10/+25	V	Absolute maximum values, AC ( $f > 1\text{ Hz}$ )	Note: 1
$V_{GSop}$	Gate - Source Voltage	-5/+20	V	Recommended operational values	Note: 2
$I_D$	Continuous Drain Current	75	A	$V_{GS} = 20\text{ V}, T_C = 25^\circ\text{C}$	Fig. 19
		48		$V_{GS} = 20\text{ V}, T_C = 100^\circ\text{C}$	
$I_{D(pulse)}$	Pulsed Drain Current	160	A	Pulse width $t_p$ limited by $T_{Jmax}$	Fig. 22
$P_D$	Power Dissipation	338	W	$T_C = 25^\circ\text{C}, T_J = 150^\circ\text{C}$	Fig. 20
$T_J, T_{stg}$	Operating Junction and Storage Temperature	-40 to +150	$^\circ\text{C}$		
$T_L$	Solder Temperature	260	$^\circ\text{C}$	1.6mm (0.063") from case for 10s	

Note (1): When using MOSFET Body Diode  $V_{GSmax} = -5\text{V}/+25\text{V}$

Note (2): MOSFET can also safely operate at 0/+20V

**Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	1700			V	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	
$V_{GS(th)}$	Gate Threshold Voltage	2.0	3.0	4	V	$V_{DS} = V_{GS}, I_D = 18\text{mA}$	Fig. 11
			2.5		V	$V_{DS} = V_{GS}, I_D = 18\text{mA}, T_J = 150^\circ\text{C}$	
$I_{DSS}$	Zero Gate Voltage Drain Current		2	100	$\mu\text{A}$	$V_{DS} = 1700\text{ V}, V_{GS} = 0\text{ V}$	
$I_{GSS}$	Gate-Source Leakage Current			600	nA	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	
$R_{DS(on)}$	Drain-Source On-State Resistance		40	70	m $\Omega$	$V_{GS} = 20\text{ V}, I_D = 50\text{ A}$	Fig. 4,5,6
			80			$V_{GS} = 20\text{ V}, I_D = 50\text{ A}, T_J = 150^\circ\text{C}$	
$g_{fs}$	Transconductance		24.7		S	$V_{DS} = 20\text{ V}, I_{DS} = 50\text{ A}$	Fig. 7
			23.4			$V_{DS} = 20\text{ V}, I_{DS} = 50\text{ A}, T_J = 150^\circ\text{C}$	
$C_{iss}$	Input Capacitance		3455		pF	$V_{GS} = 0\text{ V}$ $V_{DS} = 1200\text{ V}$ $f = 1\text{ MHz}$ $V_{AC} = 25\text{ mV}$	Fig. 17,18
$C_{oss}$	Output Capacitance		171				
$C_{rss}$	Reverse Transfer Capacitance		6.7				
$E_{oss}$	$C_{oss}$ Stored Energy		139				Fig. 16
$C_{o(er)}$	Effective Output Capacitance (Energy Related)		188		pF	$V_{GS} = 0\text{ V}, V_{DS} = 0 \dots 1200\text{V}$	Note: 3
$C_{o(tr)}$	Effective Output Capacitance (Time Related)		255				
$E_{ON}$	Turn-On Switching Energy (SiC Diode FWD)		0.52		mJ	$V_{DS} = 1200\text{ V}, V_{GS} = -5/20\text{ V},$ $I_D = 50\text{ A}, R_{G(ext)} = 2.5\ \Omega, L = 99\ \mu\text{H},$ $T_J = 150^\circ\text{C},$ using SiC Diode as FWD	Fig. 26, 29b Note 2
$E_{OFF}$	Turn Off Switching Energy (SiC Diode FWD)		0.43				
$E_{ON}$	Turn-On Switching Energy (Body Diode FWD)		2.0		mJ	$V_{DS} = 1200\text{ V}, V_{GS} = -5/20\text{ V},$ $I_D = 50\text{ A}, R_{G(ext)} = 2.5\ \Omega, L = 99\ \mu\text{H},$ $T_J = 150^\circ\text{C},$ using MOSFET as FWD	Fig. 26, 29a Note 2
$E_{OFF}$	Turn Off Switching Energy (Body Diode FWD)		0.31				
$t_{d(on)}$	Turn-On Delay Time		15		ns	$V_{DD} = 1200\text{ V}, V_{GS} = -5/20\text{ V}$ $I_D = 50\text{ A},$ $R_{G(ext)} = 2.5\ \Omega,$ Timing relative to $V_{DS}$ Inductive load	Fig. 27, 29 Note 2
$t_r$	Rise Time		18				
$t_{d(off)}$	Turn-Off Delay Time		34				
$t_f$	Fall Time		12				
$R_{G(int)}$	Internal Gate Resistance		1.3		$\Omega$	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$	
$Q_{gs}$	Gate to Source Charge		46		nC	$V_{DS} = 1200\text{ V}, V_{GS} = -5/20\text{ V}$ $I_D = 50\text{ A}$ Per IEC60747-8-4 pg 21	Fig. 12
$Q_{gd}$	Gate to Drain Charge		71				
$Q_g$	Total Gate Charge		204				

Note (3):  $C_{o(er)}$ , a lumped capacitance that gives same stored energy as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 1200V  
 $C_{o(tr)}$ , a lumped capacitance that gives same charging time as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 1200V

### Reverse Diode Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	3.8		V	$V_{GS} = -5\text{ V}, I_{SD} = 25\text{ A}$	Fig. 8, 9, 10 Note 1
		3.4		V	$V_{GS} = -5\text{ V}, I_{SD} = 25\text{ A}, T_J = 150\text{ }^\circ\text{C}$	
$I_S$	Continuous Diode Forward Current		76	A	$V_{GS} = -5\text{ V}, T_C = 25\text{ }^\circ\text{C}$	Note 1
$I_{S,pulse}$	Diode pulse Current		160	A	$V_{GS} = -5\text{ V}$ , pulse width $t_p$ limited by $T_{jmax}$	Note 1
$t_{rr}$	Reverse Recovery Time	44		ns	$V_{GS} = -5\text{ V}, I_{SD} = 50\text{ A}, V_R = 1200\text{ V}$ $dif/dt = 3000\text{ A}/\mu\text{s}, T_J = 150\text{ }^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	1.9		$\mu\text{C}$		
$I_{rrm}$	Peak Reverse Recovery Current	64		A		
$t_{rr}$	Reverse Recovery Time	25		ns	$V_{GS} = -5\text{ V}, I_{SD} = 50\text{ A}, V_R = 1200\text{ V}$ $dif/dt = 13450\text{ A}/\mu\text{s}, T_J = 150\text{ }^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	2.4		$\mu\text{C}$		
$I_{rrm}$	Peak Reverse Recovery Current	166		A		

### Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.22	0.37	$^\circ\text{C}/\text{W}$		Fig. 21
$R_{\theta JC}$	Thermal Resistance from Junction to Ambient		40			

Typical Performance

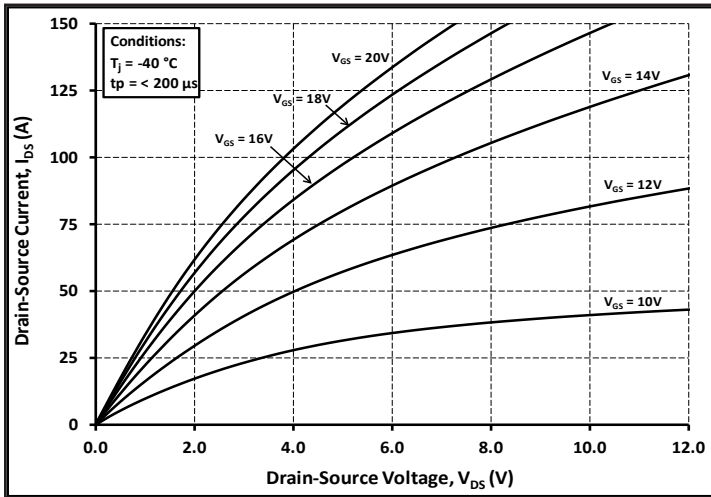


Figure 1. Output Characteristics  $T_J = -40\text{ }^\circ\text{C}$

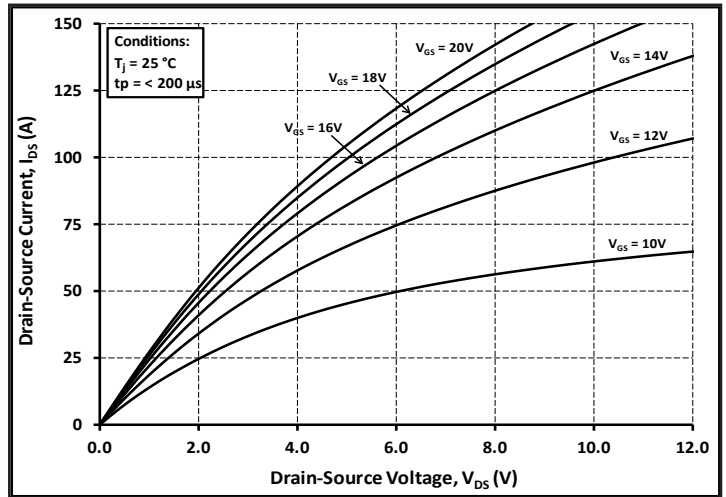


Figure 2. Output Characteristics  $T_J = 25\text{ }^\circ\text{C}$

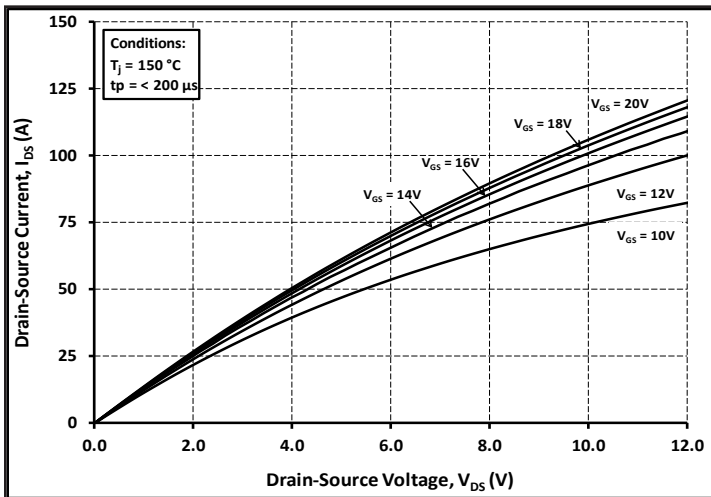


Figure 3. Output Characteristics  $T_J = 150\text{ }^\circ\text{C}$

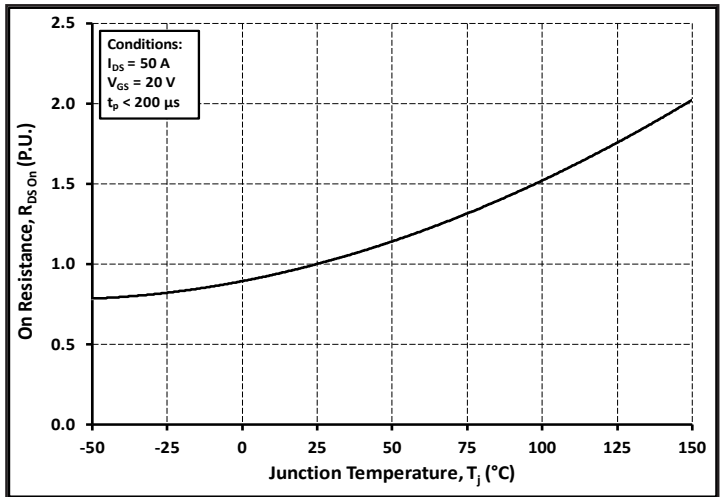


Figure 4. Normalized On-Resistance vs. Temperature

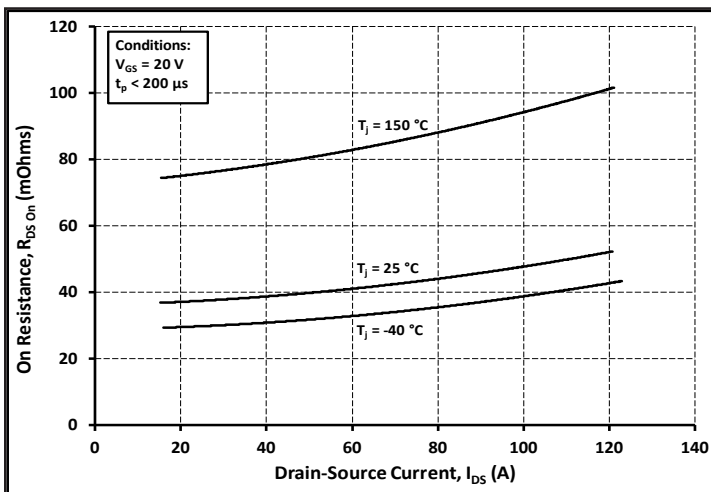


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

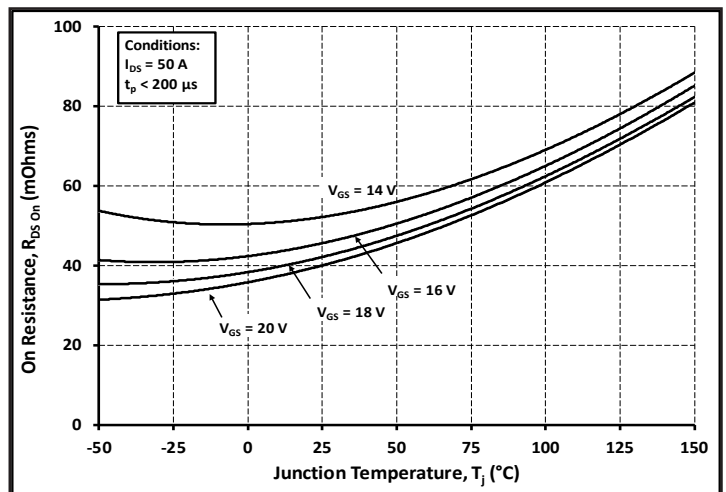


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

**Typical Performance**

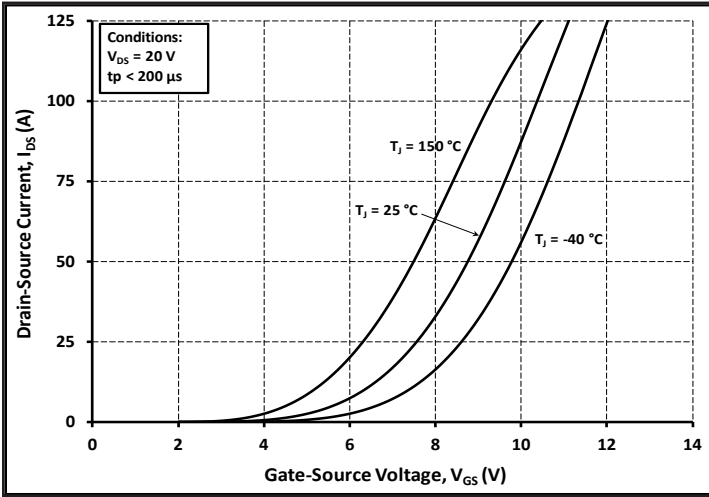


Figure 7. Transfer Characteristic For Various Junction Temperatures

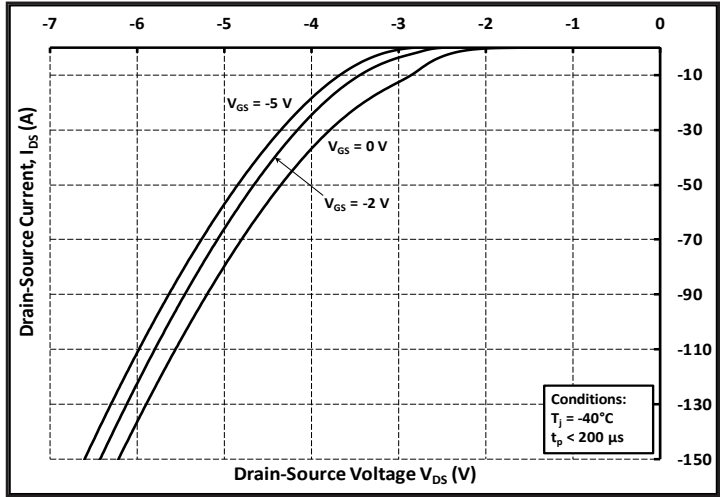


Figure 8. Body Diode Characteristic at -40 °C

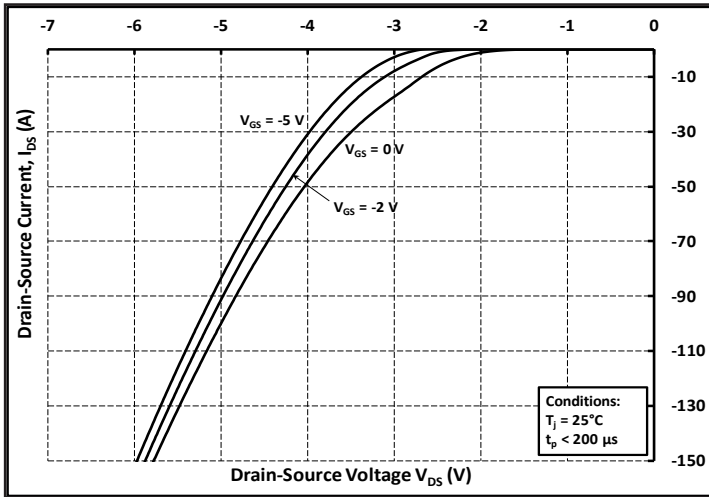


Figure 9. Body Diode Characteristic at 25 °C

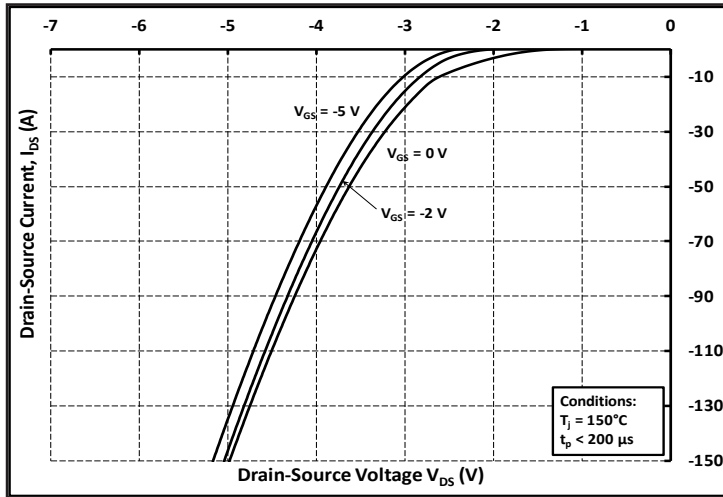


Figure 10. Body Diode Characteristic at 150 °C

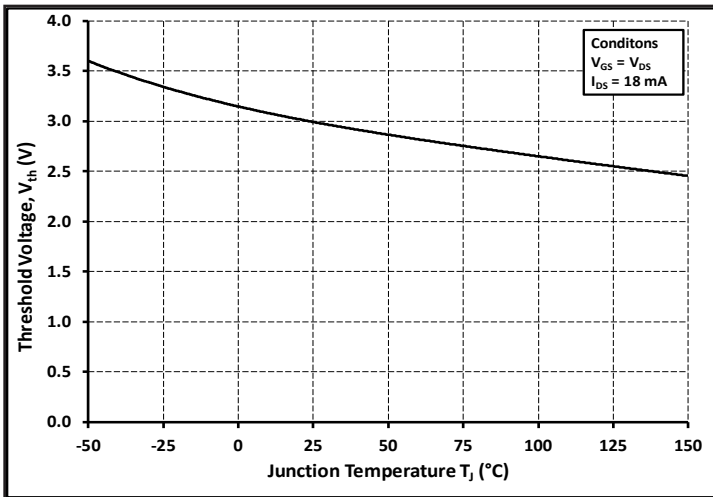


Figure 11. Threshold Voltage vs. Temperature

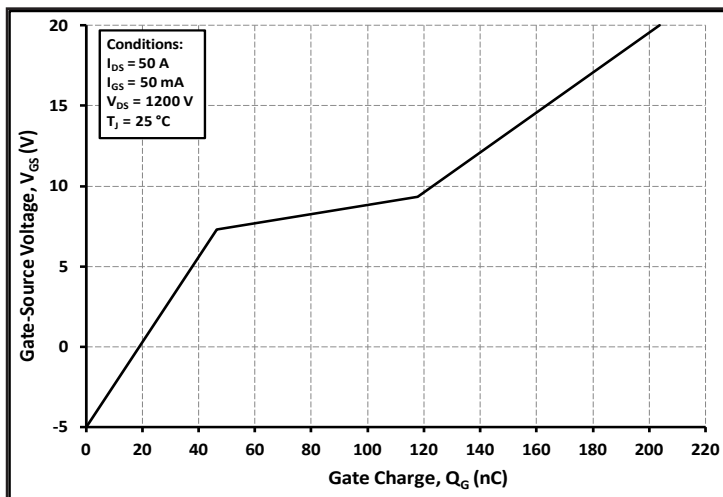


Figure 12. Gate Charge Characteristic

**Typical Performance**

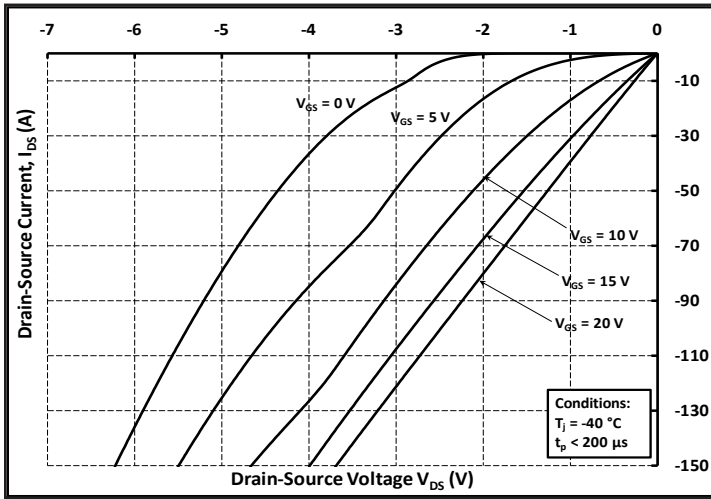


Figure 13. 3rd Quadrant Characteristic at -40 °C

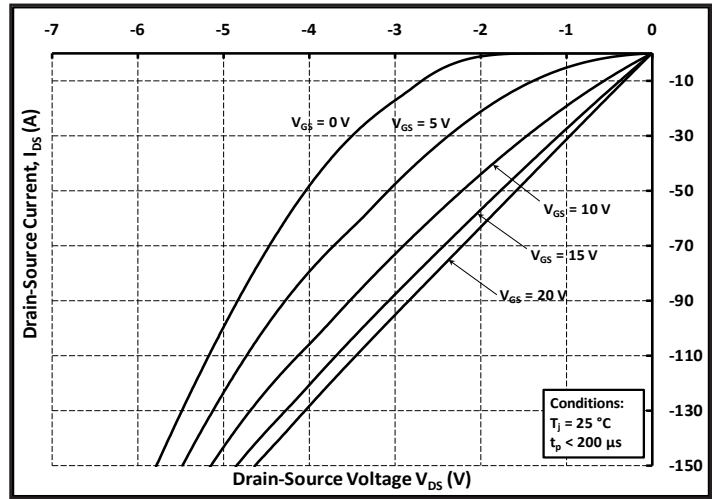


Figure 14. 3rd Quadrant Characteristic at 25 °C

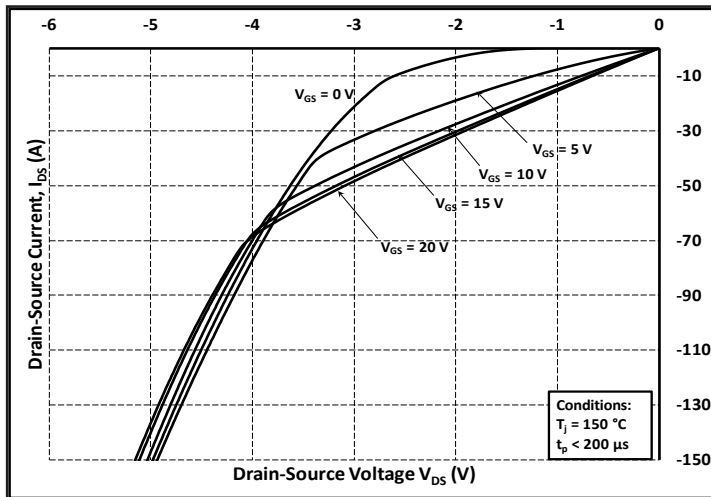


Figure 15. 3rd Quadrant Characteristic at 150 °C

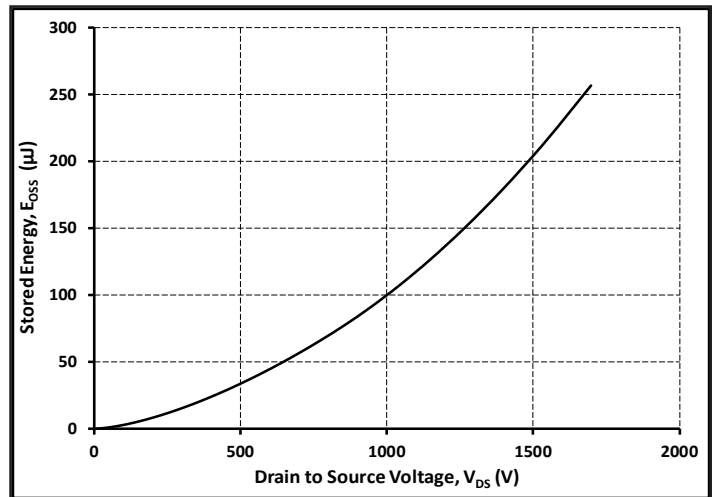


Figure 16. Output Capacitor Stored Energy

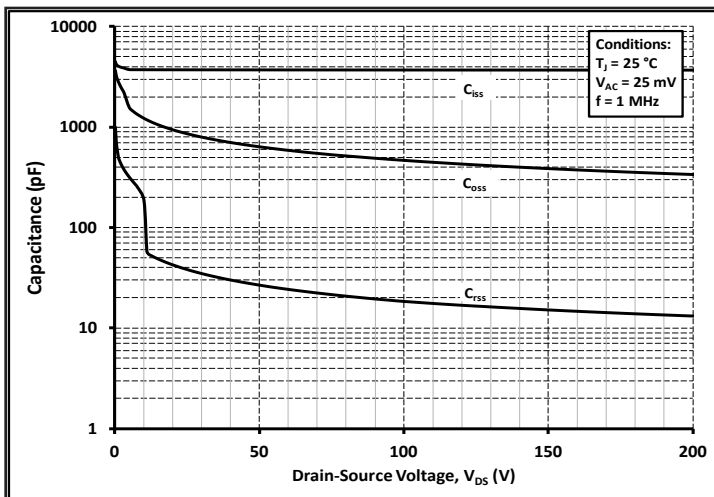


Figure 17. Capacitances vs. Drain-Source Voltage (0-200 V)

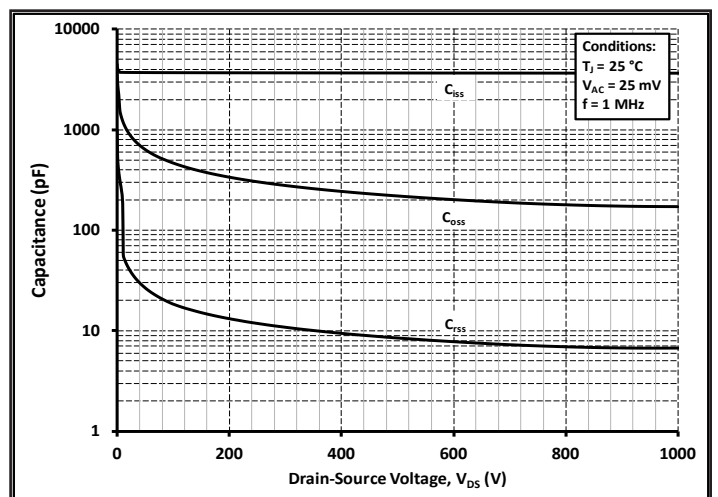


Figure 18. Capacitances vs. Drain-Source Voltage (0-1000 V)

Typical Performance

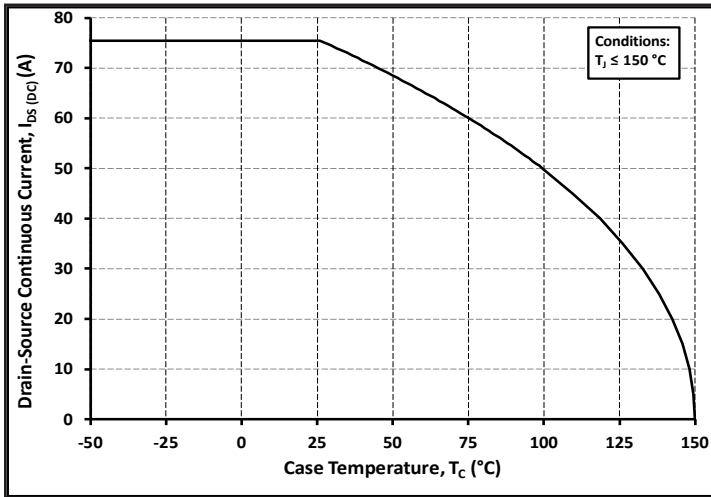


Figure 19. Continuous Drain Current Derating vs. Case Temperature

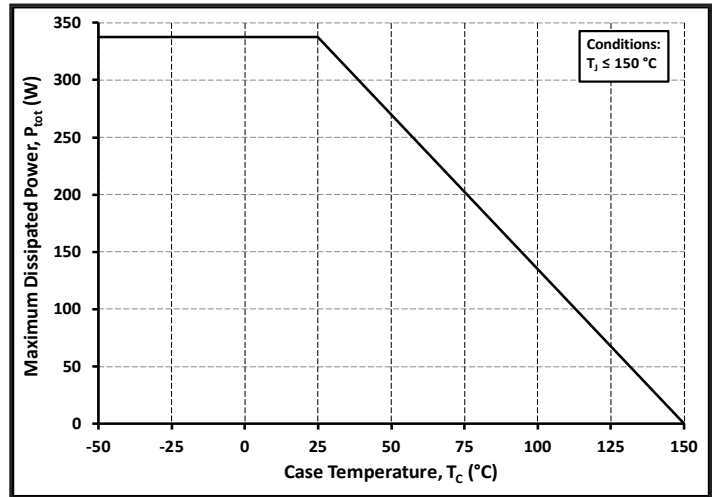


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

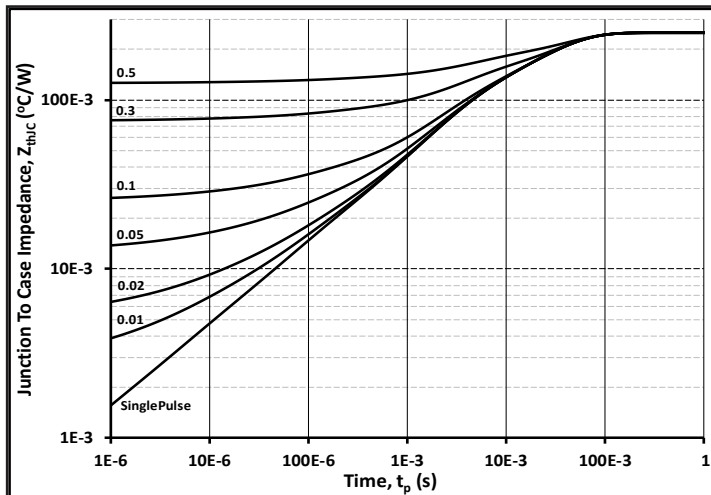


Figure 21. Transient Thermal Impedance (Junction - Case)

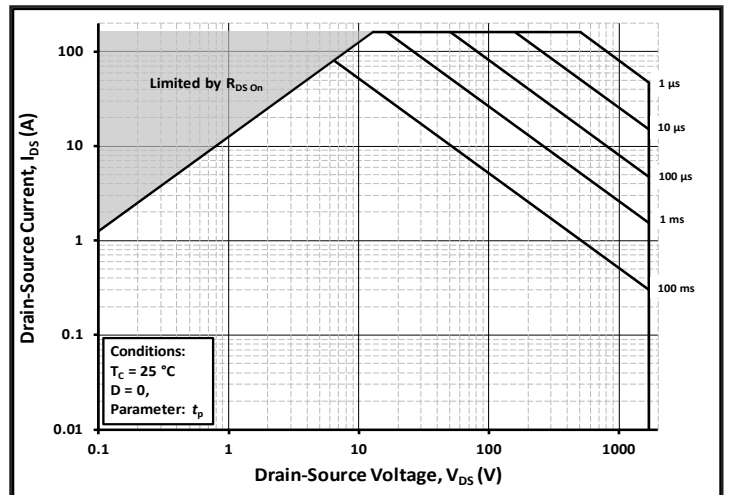


Figure 22. Safe Operating Area

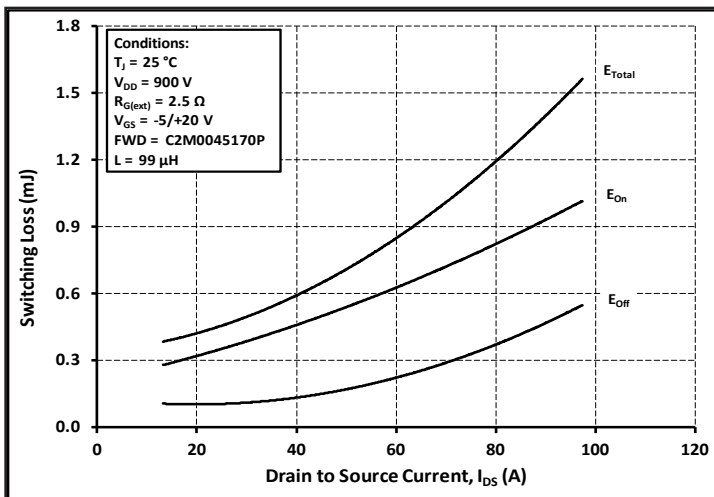


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 900V$ )

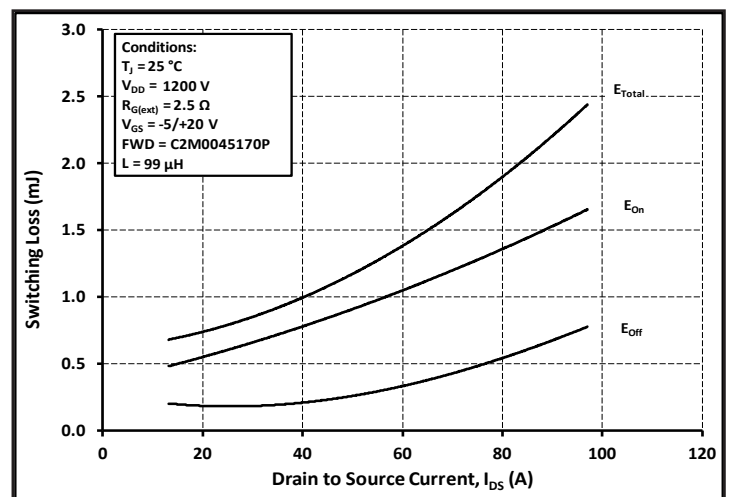


Figure 24. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 1200V$ )

Typical Performance

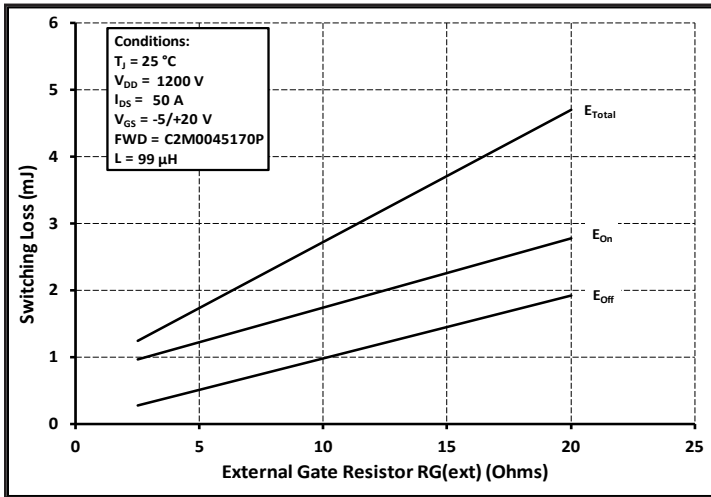


Figure 25. Clamped Inductive Switching Energy vs.  $R_{G(ext)}$

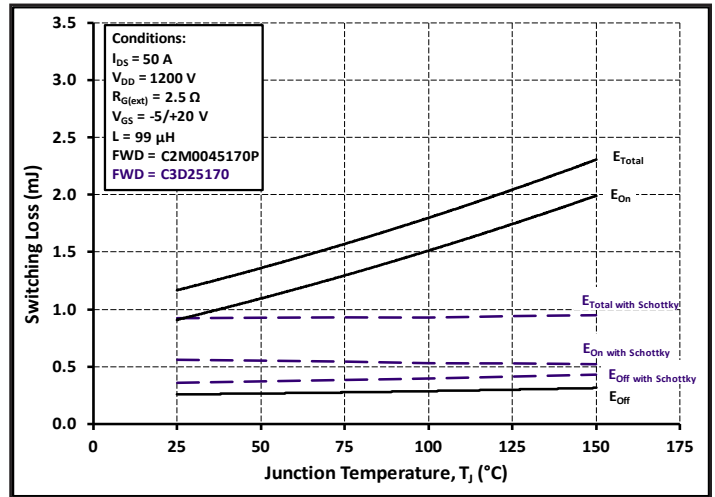


Figure 26. Clamped Inductive Switching Energy vs. Temperature

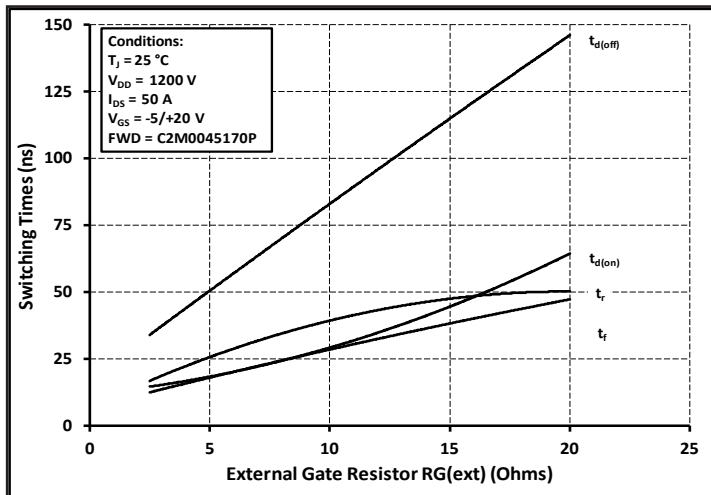


Figure 27. Switching Times vs.  $R_{G(ext)}$

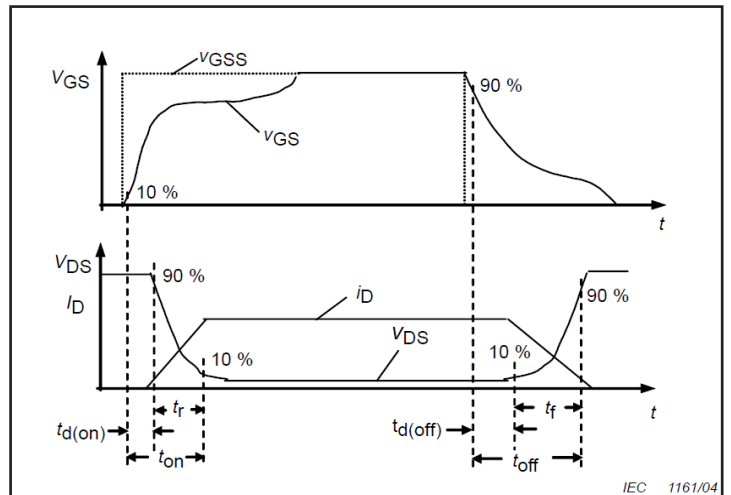


Figure 28. Switching Times Definition



**Test Circuit Schematic**

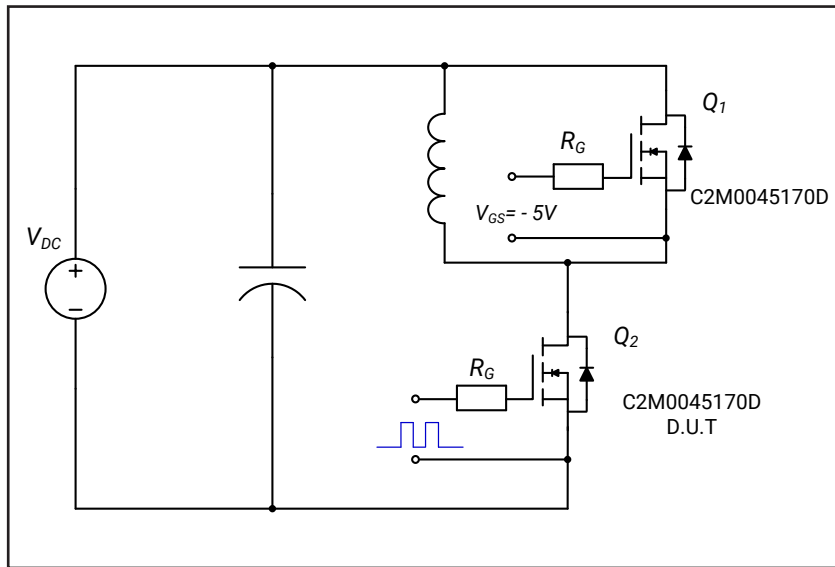


Figure 29a. Clamped Inductive Switching Test Circuit using MOSFET intrinsic body diode

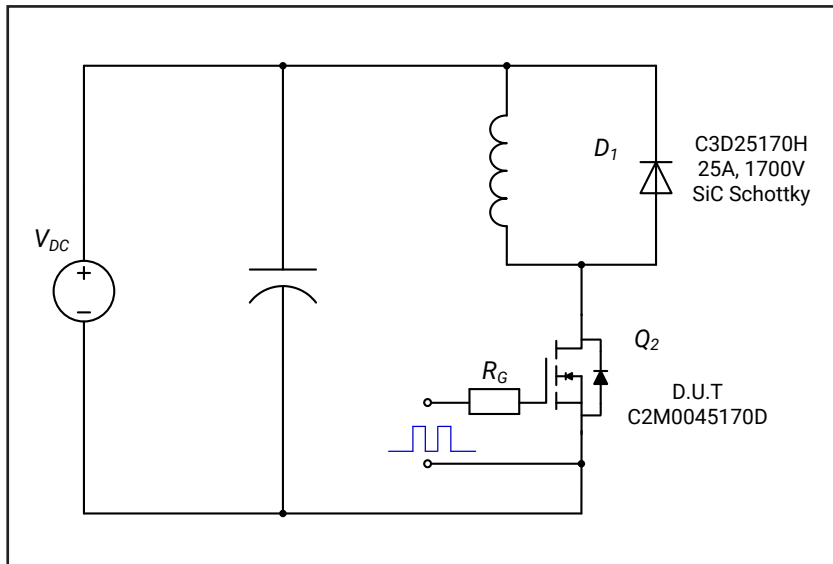
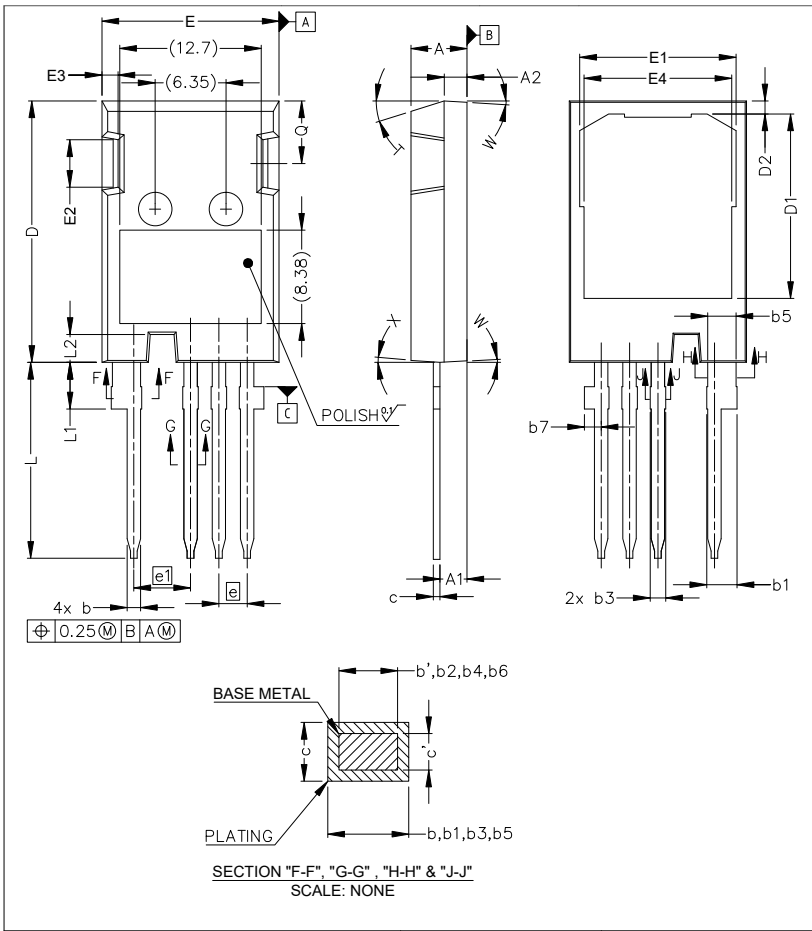


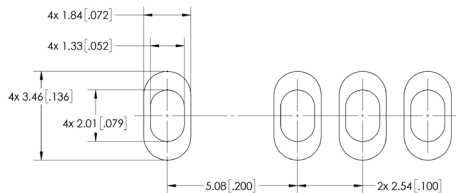
Figure 29b. Clamped Inductive Switching Test Circuit using SiC Schottky diode

**Package Dimensions**



SYM	MILLIMETERS	
	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b'	1.07	1.28
b	1.07	1.33
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
b7	1.30	1.70
c'	0.55	0.65
c	0.55	0.68
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54 BSC	
e1	5.08 BSC	
N*	4	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
Q	5.49	6.00
T	17.5° REF.	
W	3.5° REF.	
X	4° REF.	

**Recommended Solder Pad Layout**



**Revision history**

Document Version	Date of release	Description of changes
Rev -	April - 2018	Initial datasheet
Rev 1	NA	Revision 1 not released.
Rev 2	May - 2022	Added effective output capacitance, Typical values updated to support PCN-1278.

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